SHOULDER

规格书编号 SPEC NO:

产品规格书 SPECIFICATION

CUSTOMER 客户:		
PRODUCT 产品:	SAW FILTER	
MODEL NO 型 号:	HDF497F-F11	
PREPARED 编 制:	CHECKED 审 核:	
APPROVED 批 准:	D A T E 日 期:	2013-6-27

客户确认 CUSTOMER RECEIVED:				
审核 CHECKED	批准 APPROVED	日期 DATE		

无锡市好达电子有限公司 Shoulder Electronics Limited

SAW FILTER

HDF497F-F11

更改历史记录 History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark



1. SCOPE

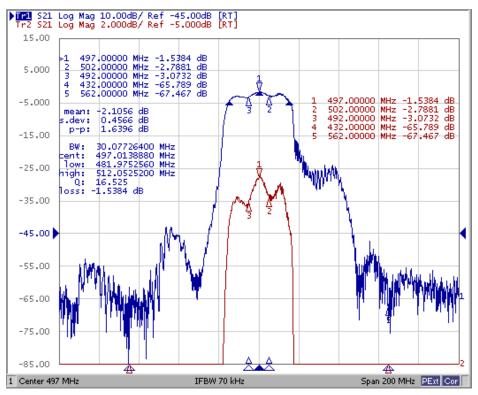
This specification shall cover the characteristics of SAW filter With F497F used for the page system.

2. ELECTRICAL SPECIFICATION

Operation Temperature Range	-40°C to +85°C	
Storage Temperature Range	-40°C to +85°C	
Maximum DC Voltage	10 V	
Maximum Input Power	10 dBm	

Electronic Characteristics

2-1. Typical frequency response

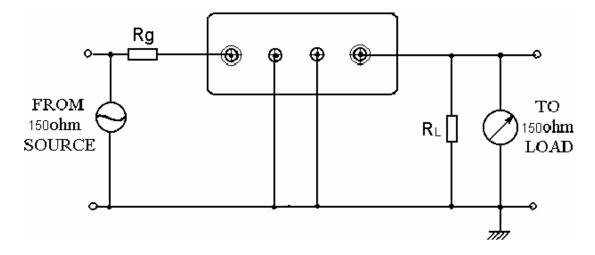


2-2.Electrical characteristics

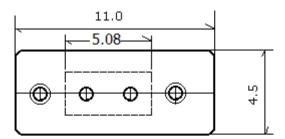
	Unit	Minimum	Typical	Maximum
Center Frequency	MHz	-	497	-
Insertion Loss (497±5 MHz)	dB		3.0	5.0
Amplitude Ripple (497 \pm 5 MHz)	dB		1.0	2.0
-3dB bandwidth	MHz		28	
Attenuation				
Fc-200~ Fc -100 MHz	dB	40	50	-
Fc +60~ Fc +200MHz		40	50	
Input/Output Impedance	Ohms		150	

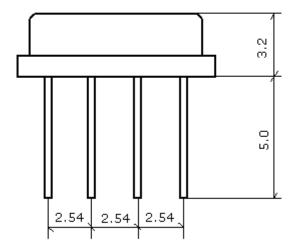
HDF497F-F11

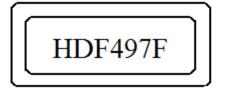
3. TEST CIRCUIT



4. DIMENSION







5. ENVIRONMENTAL CHARACTERISTICS

5-1 High temperature exposure

Subject the device to $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

5-2 Low temperature exposure

Subject the device to -40° C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 2-2.

5-3 Temperature cycling

Subject the device to a low temperature of -40° C for 30 minutes. Following by a high temperature of $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 2-2.

5-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at 260° C $\pm 10^{\circ}$ C for 10 ± 1 sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 2-2.

5-5 Solderability

Subject the device terminals into the solder bath at $245^{\circ}C \pm 5^{\circ}C$ for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 2-2.

5-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 2-2.

5-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 2-2.

6. REMARK

6.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

6.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

6.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.